## Notice of References Cited Application/Control No. 10/585,875 Applicant(s)/Patent Under Reexamination OGINO ET AL. Examiner Edu E. Enin-Okut 1795 Applicant(s)/Patent Under Reexamination OGINO ET AL.

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,128,700	12-1978	Sederquist, Richard A.	429/17
*	В	US-2002/0031450	03-2002	YAMASHITA et al.	429/17
*	C	US-5,441,821	08-1995	Merritt et al.	429/17
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Η	US-			
	-	US-			
	J	US-			
	К	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	JP 2000195534 A	07-2000	Japan	AOYAMA, SATOSHI	H01M 8/06,3/38,8/04
	0	JP 10144335 A	05-1998	Japan	IKEDA et al.	H01M 8/06,8/04
	Ρ					
	Ø					
	R					
	s					
	Τ					

## **NON-PATENT DOCUMENTS**

	NON-I ATENT BOOOMENTO						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U	"ammeter." Merriam-Webster Online Dictionary. Accessed on November 23, 2009 from <a href="http://www.merriam-webster.com/dictionary/ammeter">http://www.merriam-webster.com/dictionary/ammeter</a> .					
	<b>V</b>						
	w						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.